

# Search Notes



Application/Control No.

10/687,096

Examiner

Sara W. Crane

Applicant(s)/Patent under Reexamination

VOELZ, JAMES L.

Art Unit

2811

## SEARCHED

Class	Subclass	Date	Examiner
257	669	4/05	SWC
update		5/06	SWC

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

EAST	DATE	EXMR
(backside adj coating) and wafer, printed circuit, (wafer adj scale)	4/05	SWC
update see printout	5/06	SWC